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INFORMATION DISCLOSURE STATEMENT

Applicant: Boaz KENAN et al.

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UB	Martino, R., et al., "Application of the Aerial Image Measurement System (AIMS TM) to the Analysis of Binar Mask Imaging and Resolution Enhancement Techniques," <i>SPIE</i> , vol. 2197, January, 1994, pp. 573-584. Ferguson, Richard A., et al., "Application of an Aerial Image Measurement System to Mask Fabrication and Actional Image Measurement System (AIMS TM) to the Analysis of Binary Mask Imaging and Resolution Enhancement Techniques," <i>SPIE</i> , vol. 2197, January, 1994, pp. 573-584.					
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